Sparch Notes

_	Search Notes						
	Ш	Ш					Ш
	Ш	Ш				Ш	Ш

Appli	cation	/Control	No.

Applicant(s)/Patent under Reexamination

SEATTLE ET AL.

09/602,247

Examiner

Art Unit

Paul Nguyen-Ba

2176

SEAR	CHED	
Subclass	Date	Examiner
523 530-533 540 542 500	11/3/2005	PNB
	Subclass 523 530-533 540 542	523 530-533 540 11/3/2005 542

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
<u> </u>					
	L				

(INCLUDING SEARCH STRATEGY)					
		DATE	EXMR		
USPAT US-PGPUB EPO JPO DERWENT IBM_TDB	*2 **	11/3/2005	PNB		
NPL SEARCH - ACM Database		11/3/2005	PNB		